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Testing of Software and Communicating Systems

20th IFIP TC 6/WG 6.1 International Conference, TestCom 2008
8th International Workshop, FATES 2008
Tokyo, Japan, June 10-13, 2008
Proceedings

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Preface

This volume contains the proceedings of TESTCOM/FATES 2008, a joint conference of two communities: TESTCOM was the 20th edition of the IFIP TC6/WG6.1 International Conference on Testing of Communicating Systems and FATES was the 8th edition of the International Workshop on Formal Approaches to Testing of Software. TESTCOM/FATES 2008 was held at the Campus Innovation Center in Tokyo, Japan during June 10–13, 2008.

Testing is one of the most important techniques for validating and checking the correctness of communication and software systems. Testing, however, is also a laborious and very cost-intensive task during the development process of such systems. TESTCOM is a series of international conferences addressing the problems of testing communicating systems, including communication protocols, services, distributed platforms, and middleware. FATES is a series of international workshops discussing the challenges of using rigorous and formal methods for testing software systems in general. TESTCOM/FATES aims at being a forum for researchers, developers, and testers to review, discuss, and learn about new approaches, concepts, theories, methodologies, tools, and experiences in the field of testing of communicating systems and software.

TESTCOM has a long history. Previously it was called the International Workshop on Protocol Test Systems (IWPTS) and changed its name to the International Workshop on Testing of Communicating System (IWTCS) later. The previous conferences were held in Vancouver, Canada (1988); Berlin, Germany (1989); McLean, USA (1990); Leidschendam, The Netherlands (1991); Montréal, Canada (1992); Pau, France (1993); Tokyo, Japan (1994); Evry, France (1995); Darmstadt, Germany (1996); Cheju Island, Korea (1997); Tomsk, Russia (1998); Budapest, Hungary (1999); Ottawa, Canada (2000); Berlin, Germany (2001); Sophia Antipolis, France (2002); Oxford, UK (2004); Montréal, Canada (2005); New York, USA (2006) and Tallinn, Estonia (2007).

FATES also has its history. The previous workshops were held in Aalborg, Denmark (2001); Brno, Czech Republic (2002); Montréal, Canada (2003); Linz, Austria (2004); Edinburgh, UK (2005); Seattle, USA (2006), and Tallinn, Estonia (2007). TESTCOM and FATES became a joint conference in 2007.

In addition, FORTE 2008, the 28th IFIP International Conference on Formal Methods for Networked and Distributed Systems, was also held at the same place and time, as it did last year. Thus, the co-location of TESTCOM/FATES and FORTE fostered the collaboration between different communities. The common spirit of both conferences was underpinned by joint opening and closing sessions, invited talks, as well as joint social events.

TESTCOM/FATES received a reasonable number of submissions this year. Initially 58 abstracts were submitted, from which 42 research full papers were elaborated. The Program Committee finally selected 18 papers for presentation at the

conference. Together with the invited presentations by Yutaka Yasuda from KDDI Corporation, Japan, and Paul Baker from Motorola, UK, they formed the contents of the proceedings. In addition, the conference contained another invited presentation on behalf of FORTE by Wolfram Schulte from Microsoft Research, USA. Moreover, presentations on industrial best practices and work-in-progress presentations rounded off the conference. A tutorial day preceded the conference.

It took tremendous efforts to organize this event. We would like to thank all the contributors for the success of TESTCOM/FATES 2008. In particular we are grateful to the Steering Committee of IFIP TESTCOM, the Program Committee, and all reviewers for their support in selecting papers of high quality. Without these contributions, these proceedings would not exist. We thank the International Communications Foundation, Support Center for Advanced Telecommunications Technology Research, Foundation, Microsoft Research, and KDDI Corporation for their financial support and Springer for publishing the proceedings. Last but not least, we would also like to express our thanks to the members of the Local Arrangements team from KDDI R&D Laboratories Inc., The University of Electro-Communications, Osaka University, and the Nara Institute of Science and Technology for their continuous support of this conference.

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March 2008

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